TOSHIBA Field Effect Transistor Silicon P/N Channel MOS Type (P Channel U-MOSII/N Channel U-MOSII)

TPC8403

Motor Drive Applications
Notebook PC Applications

Portable Equipment Applications

• Low drain-source ON resistance: P Channel RDS (ON) = $45 \text{ m}\Omega$ (typ.)

N Channel RDS (ON) = $25 \text{ m}\Omega$ (typ.)

• High forward transfer admittance: P Channel $|Y_{fs}| = 6.2 \text{ S (typ.)}$

N Channel $|Y_{fs}| = 7.8 \text{ S (typ.)}$

• Low leakage current: P Channel IDSS = $-10 \mu A (V_{DS} = -30 V)$

N Channel IDSS = $10 \mu A (VDS = 30 V)$

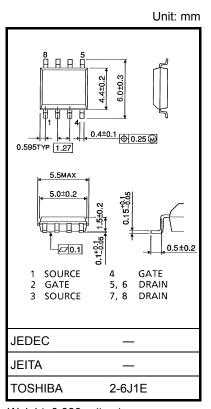
• Enhancement mode

: P Channel $V_{th} = -1.0 \sim -2.2 \text{ V } (V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA})$

: N Channel $V_{th} = 1.3 \sim 2.5 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

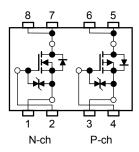
Absolute Maximum Ratings (Ta = 25°C)

С	Symbol	Rat	Unit			
J	Symbol	P Channel	N Channel	o iii		
Drain-source v	V _{DSS}	-30	30	V		
Drain-gate vol	tage (R _{GS} = 20 kΩ)	V_{DGR}	-30	30	٧	
Gate-source v	oltage	V _{GSS}	±20	±20	٧	
Drain current	DC (Note 1)	I _D	-4.5	6	А	
Diain current	Pulse (Note 1)	I _{DP}	-18	24	A	
Drain power dissipation (t = 10s) (Note 2a)	Single-device operation (Note 3a)	P _{D(1)}	1.5	1.5	W	
	Single-device value at dual operation (Note 3b)	P _{D(2)}	1.1	1.1		
Drain power dissipation	Single-device operation (Note 3a)	P _{D(1)}	0.75	0.75		
(t = 10s) (Note 2b)	Single-device value at dual operation (Note 3b)	P _{D(2)}	0.45	0.45		
Single pulse avalanche energy		E _{AS}	26.3 (Note 4a)	46.8 (Note 4b)	mJ	
Avalanche cur	I _{AR}	-4.5	6	Α		
Repetitive avalanche energy Single-device value at operation (Note 2a, 3b, 5)		E _{AR}	0.11		mJ	
Channel temp	T _{ch}	150		°C		
Storage temper	erature range	T _{stg}	−55~150		°Ç	



Weight: 0.080 g (typ.)

Circuit Configuration



Note: Note 1, Note 2ab, Note 3ab, Note 4and Note 5: See the next page.

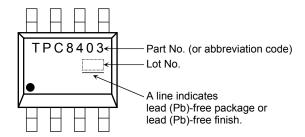
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Please handle with caution.

Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 10s) (Note 2a)	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	83.3	
	Single-device value at dual operation (Note 3b)	R _{th} (ch-a) (2)	114	°C/W
Thermal resistance, channel to ambient (t = 10s) (Note 2b)	Single-device operation (Note 2a)	R _{th (ch-a) (1)}	167	C/VV
	Single-device value at dual operation (Note 2b)	R _{th (ch-a) (2)}	278	

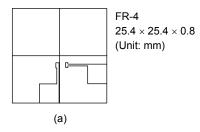
Marking

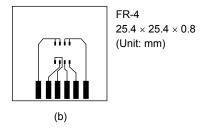


Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:

- a) Device mounted on a glass-epoxy board (a)
- b) Device mounted on a glass-epoxy board (b)





Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.).
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.).

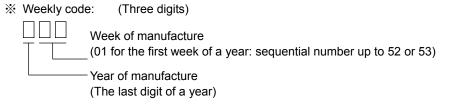
Note 4:

a)
$$V_{DD} = -24 \text{ V}$$
, $T_{ch} = 25 ^{\circ}\text{C}$ (Initial), $L = 1.0 \text{ mH}$, $R_G = 25 \Omega$, $I_{AR} = -4.5 \text{ A}$

b)
$$V_{DD} = 24~V$$
, $T_{ch} = 25^{\circ}C$ (Initial), $L = 1.0~mH$, $R_G = 25~\Omega$, $I_{AR} = 6.0~A$

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: • on lower left of the marking indicates Pin 1.





Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cut-OFF cu	rrent	I _{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-10	μА
Drain-source breakdown voltage		V _{(BR) DSS}	$I_D = -10$ mA, $V_{GS} = 0$ V	-30	_	_	V
		V _{(BR) DSX}	$I_D = -10 \text{ mA}, V_{GS} = 20 \text{ V}$	-15	_	_	v
Gate threshold vo	oltage	V _{th}	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-1.0	_	-2.2	V
Drain-source ON	registance	Dec (av)	$V_{GS} = -4.5 \text{ V}, I_D = -2.2 \text{ A}$	_	66	90	mΩ
Dialii-source ON	resistance	R _{DS} (ON)	V _{GS} = -10 V, I _D = -2.2 A	_	45	55	
Forward transfer admittance		Y _{fs}	$V_{DS} = -10 \text{ V}, I_D = -2.2 \text{ A}$	3.1	6.2	_	S
Input capacitance		C _{iss}	V _{DS} = -10 V, V _{GS} = 0 V, f = 1 MHz	_	940	_	pF
Reverse transfer capacitance		C _{rss}			270	_	
Output capacitance		Coss		_	390	_	
Switching time	Rise time	t _r	V_{GS} 0 V O	_	13	_	
	Turn-ON time	t _{on}		10 V OUT RL = 21	21	_	no
	Fall time	t _f		_	25	_	ns
	Turn-OFF time	t _{off}			73	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -24 \text{ V}, V_{GS} = -10 \text{ V},$ $I_{D} = -4.5 \text{ A}$	_	18	_	
Gate-source charge 1		Q _{gs} 1			4	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	4	_	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	-18	Α
Forward voltage (diode)		V _{DSF}	I _{DR} = -4.5 A, V _{GS} = 0 V	_	_	1.2	V

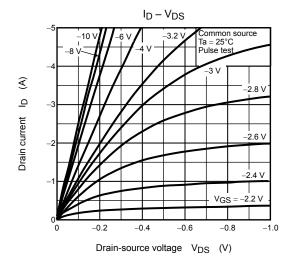


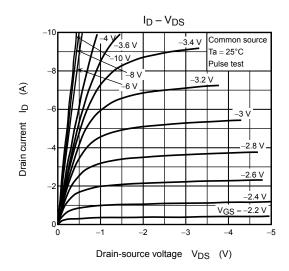
Electrical Characteristics (Ta = 25°C)

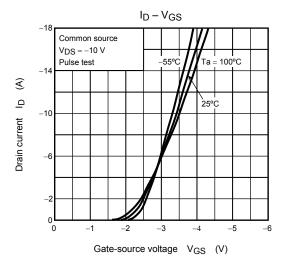
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cut-OFF current		I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V	_	_	10	μА
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	_	_	V
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	15	_	_	v
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	1.3	_	2.5	V
Drain-source ON	registance	D	V _{GS} = 4.5 V, I _D = 3 A	_	38	46	mΩ
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 3 A	_	25	33	
Forward transfer admittance		Y _{fs}	V _{DS} = 10 V, I _D = 3 A	3.9	7.8	_	S
Input capacitance		C _{iss}		_	850	_	pF
Reverse transfer capacitance		C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	180	_	
Output capacitance		Coss		_	270	_	
Switching time	Rise time	t _r	V _{GS} $\begin{array}{c} 10 \text{ V} \\ 0 \text{ V} \\ \end{array}$ $\begin{array}{c} I_D = 3.0 \text{ A} \\ 0 \text{ VOUT} \\ \end{array}$ $\begin{array}{c} R_L = \\ 5.0 \Omega \\ \end{array}$ $\begin{array}{c} 0 \text{ VOUT} \\ \text{VDD} \simeq 15 \text{ V} \\ \end{array}$ Duty $\leq 1\%$, $t_W = 10 \mu\text{s}$	_	11	_	
	Turn-ON time	t _{on}		_	18	_	- ns
	Fall time	t _f		_	6.5	_	
	Turn-OFF time	t _{off}		_	27	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \approx 24 \text{ V}, V_{GS} = 10 \text{ V},$ $I_{D} = 6 \text{ A}$	_	17	_	
Gate-source charge 1		Q _{gs} 1		_	3	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	4	_	

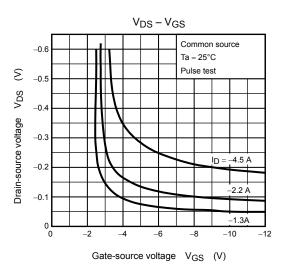
Source-Drain Ratings and Characteristics (Ta = 25°C)

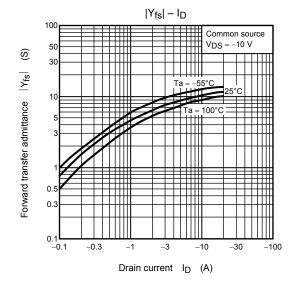
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	24	Α
Forward voltage (diode)		V _{DSF}	I _{DR} = 6 A, V _{GS} = 0 V	_	_	-1.2	V

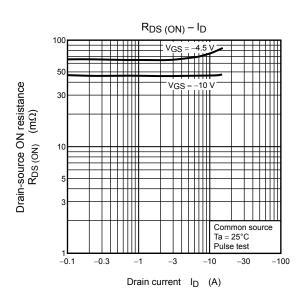


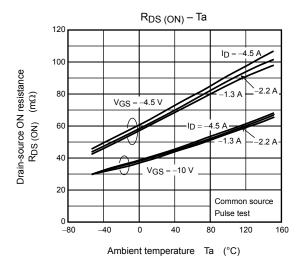


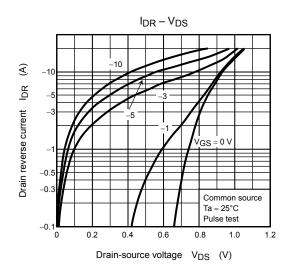


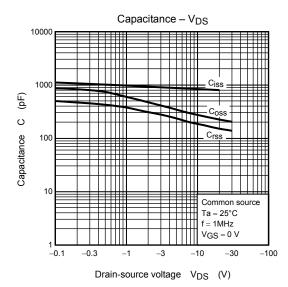


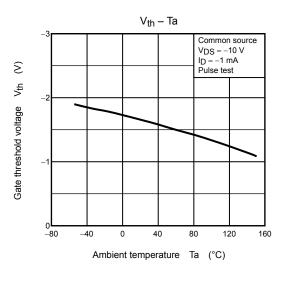


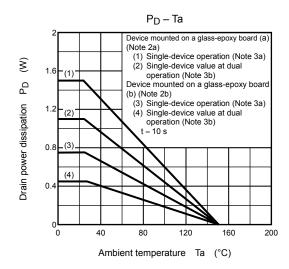


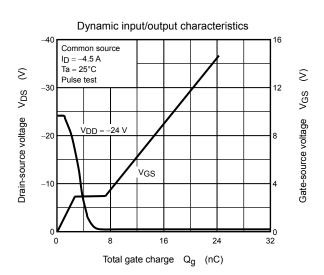


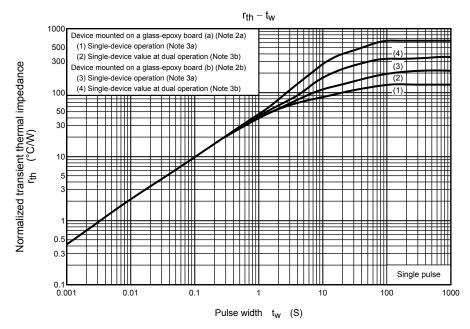




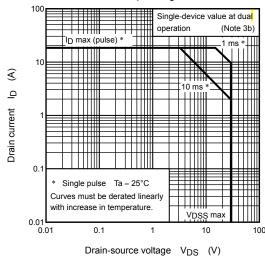




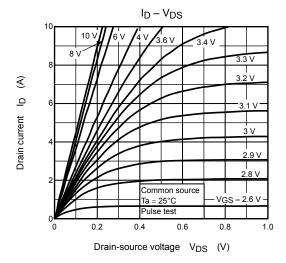


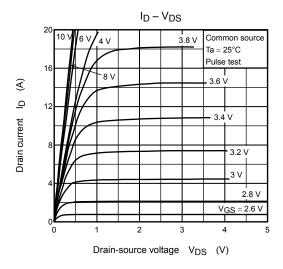


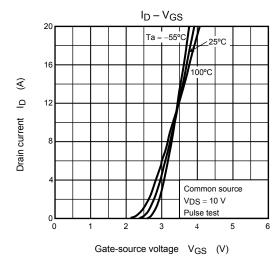


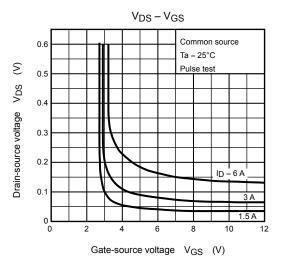


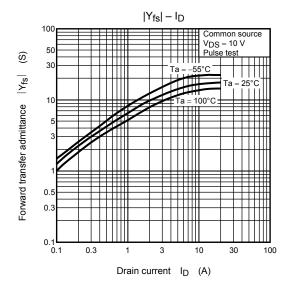
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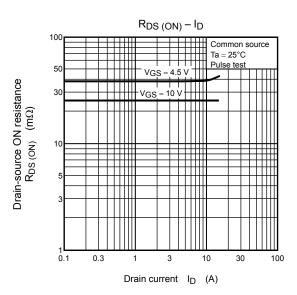


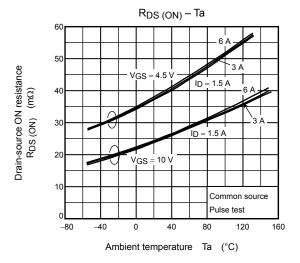


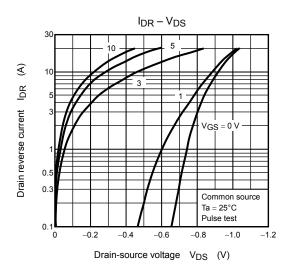


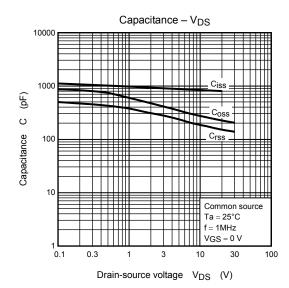


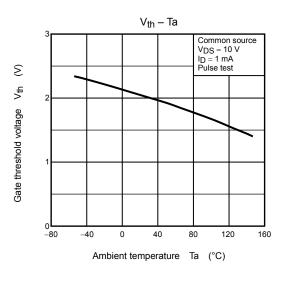


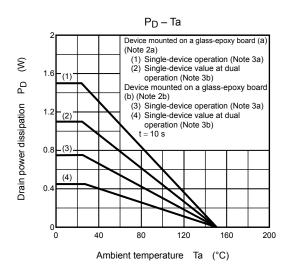


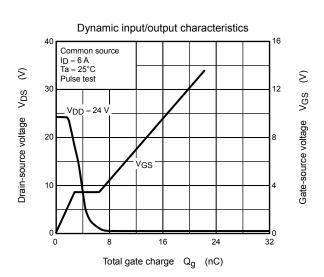


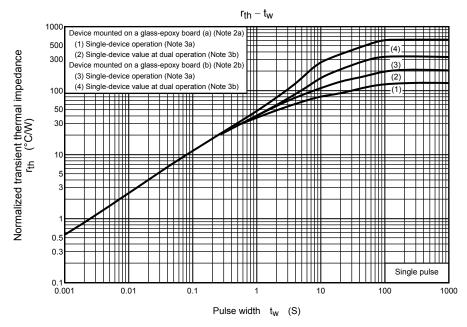




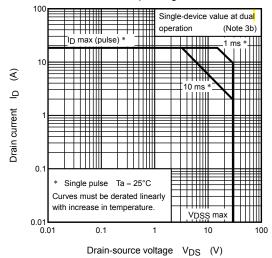












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